

Notice of References Cited	Application/Control No. 10/530,530	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner John Lambert	Art Unit 2609	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,831,547 B2	12-2004	Watarai et al.	340/5.61
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 06269065 A	09-1994	Japan	MASAKADO et al.	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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